Search Notes

Application/Control No.		Applicant(s)/Patent under Reexamination	
10/074,5	49	SINAIKO ET	AL.
Examine	r	Art Unit	
Than T	Tran	1711	

SEARCHED					
Class	Subclass	Date	Examiner		
96	15,16	12/2/2005	тт		
	95-98				
	100				
D23	333				
	351				
	355				
	364				
	366				
422	186				
	186.04				
	186.07				
	186.14				
	186.15				

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

STRATEGY	<i>,</i>
DATE	EXMR
12/2/2005	тт